

# Machine Learning (ML) Assisted IBIS-AMI Model for Optical Module Involved Advanced SerDes System Designs

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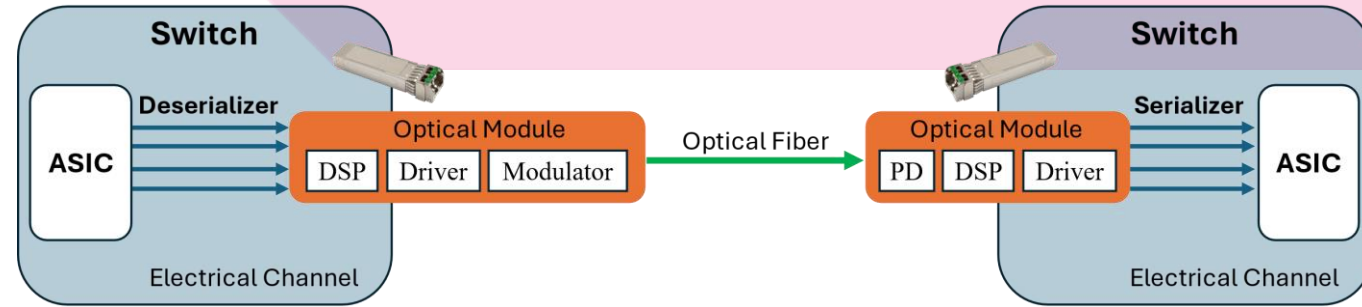
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# Motivation

## Background:

- Optical interconnects continually replace copper connections in modern communication networks to meet demands for higher bandwidth and lower power consumption.
- Signal integrity analysis for high-speed SerDes link need to model both electrical and optical modules simultaneously, to capture behaviors of optoelectronic devices, such as nonlinearity, optical dispersion and loss.



## Challenges:

- Conventional SerDes analysis solutions do not support modeling optical modules.
- Linear models, such as s-parameter, cannot accurately capture the non-linear responses of optical modules.

## Goals:

- Create accurate optical module model through standard IBIS-AMI, to facilitate signal integrity analysis for modern high-speed SerDes link.

# Solution Overview

Optical module data collection

Reduced order model generation

IBIS-AMI design/validation

Implement optical  
module design in  
circuit solver

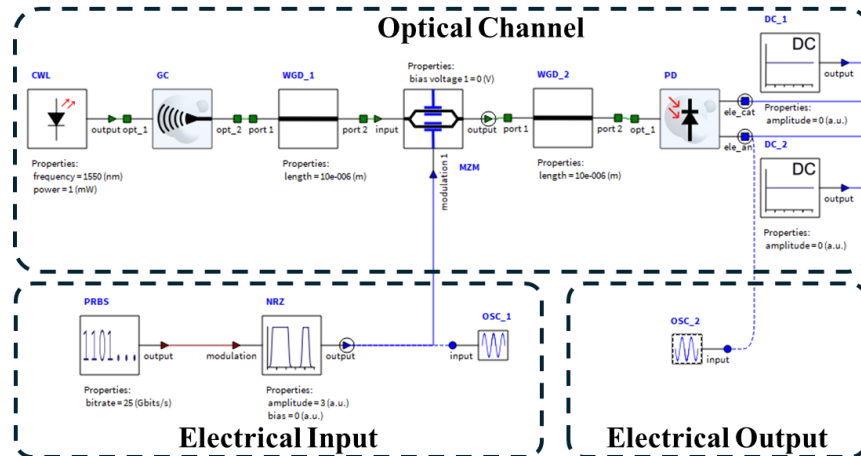
Data  
collection

FNN  
training

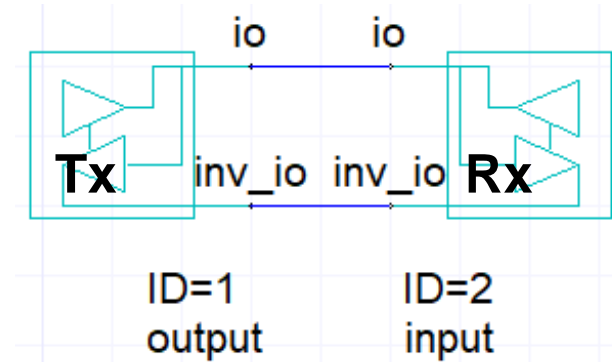
Reduced  
order model  
extraction

Build  
Custom  
AMI model

Validate AMI  
model in  
IBIS-AMI



PIC design



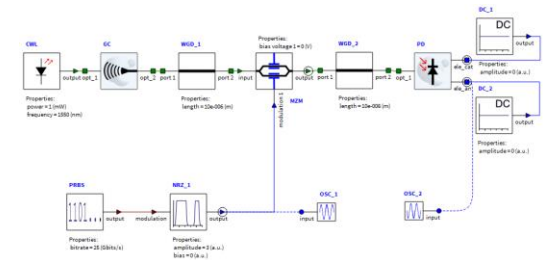
AMI model

# Automated IBIS-AMI Generation

## Optical Module Designers

## Fully Automated Model Extraction Flow

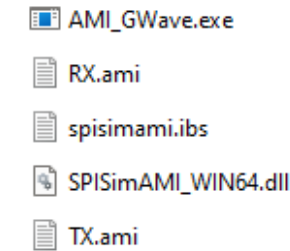
## System Designers



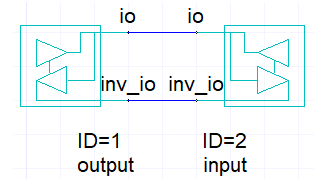
Optical module design

Data collection  
script

Reduced order model  
extraction script



AMI model package



IBIS-AMI analysis

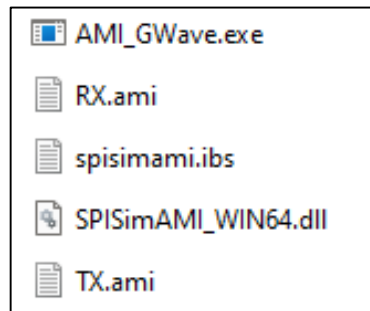
- Optical module designers implement and validate the optical module design in a commercially available circuit solver.

- Execute a data collection script to kick off the workflow.
- ML assisted reduced order model extraction will start automatically once data extraction is finished.
- A portable and ready-to-use AMI model package is automatically generated at the end of the workflow.

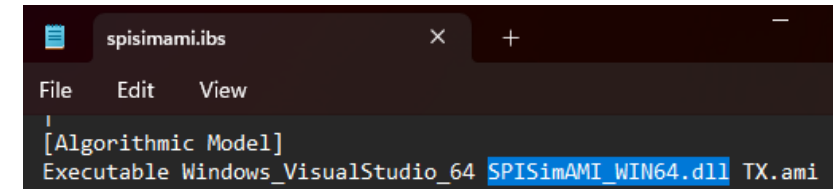
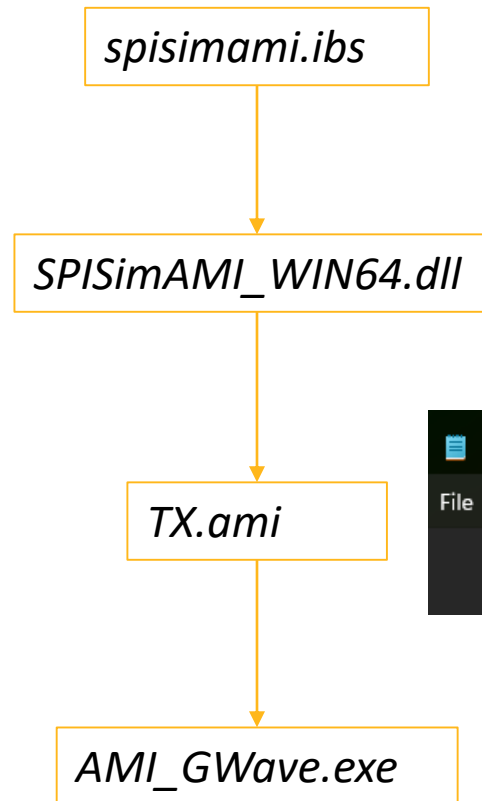
- System designers can use the AMI model to perform signal integrity analysis through standard IBIS-AMI.

# AMI model hierarchy

- The IBIS buffer is defined in .ibs file.
- .dll file interfaces the AMI model package with link analysis tools.
- AMI parameter definition (.ami) file is configured to execute the customized AMI\_GetWave().
- Reduced order model is written in AMI\_GetWave() (.exe file).

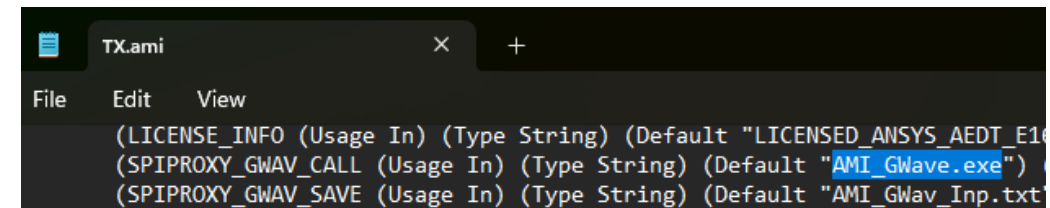


AMI model package



```
spisimami.ibs
File Edit View
[Algorithmic Model]
Executable Windows_VisualStudio_64 SPISimAMI_WIN64.dll TX.ami
```

A screenshot of a text editor window showing the content of the spisimami.ibs file. The text includes a menu bar (File, Edit, View), a section header [Algorithmic Model], and a line defining the executable: Executable Windows\_VisualStudio\_64 SPISimAMI\_WIN64.dll TX.ami.



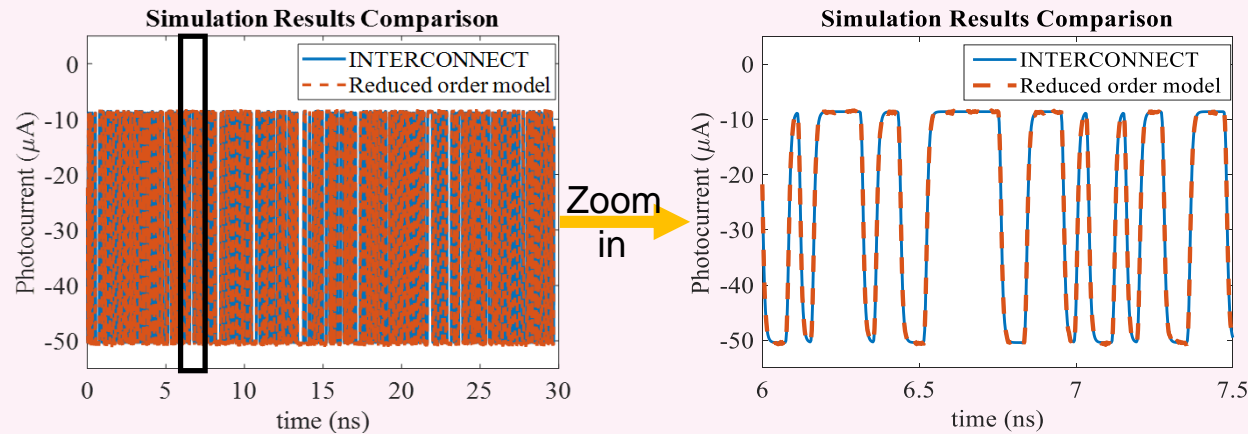
```
TX.ami
File Edit View
(LICENSE_INFO (Usage In) (Type String) (Default "LICENSED_ANSYS_AEDT_E1
(SPIPROXY_GWAV_CALL (Usage In) (Type String) (Default "AMI_GWave.exe")
(SPIPROXY_GWAV_SAVE (Usage In) (Type String) (Default "AMI_GWav_Inp.txt
```

A screenshot of a text editor window showing the content of the TX.ami file. The text includes a menu bar (File, Edit, View) and several lines of configuration parameters in parentheses, such as (LICENSE\_INFO (Usage In) (Type String) (Default "LICENSED\_ANSYS\_AEDT\_E1), (SPIPROXY\_GWAV\_CALL (Usage In) (Type String) (Default "AMI\_GWave.exe"), and (SPIPROXY\_GWAV\_SAVE (Usage In) (Type String) (Default "AMI\_GWav\_Inp.txt).

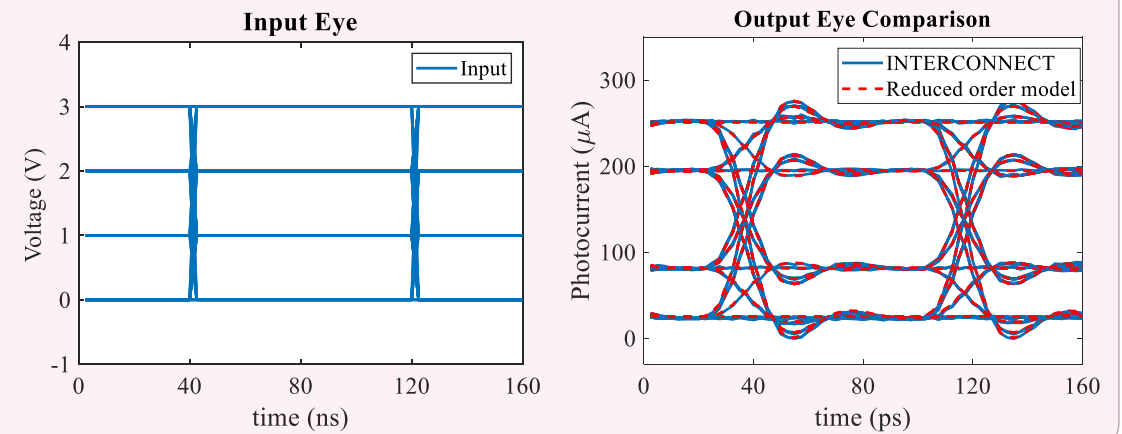
# Reduced order model accuracy

- ❖ The accuracy of reduced-order model simulations is influenced by the training accuracy of the machine learning model.
- ❖ With well trained ML process, the reduced order model simulation results closely align with the results produced by a commercially available circuit simulator, INTERCONNECT.

Transient response accuracy comparison for NRZ signals



System eye distortion for PAM4 signals



# Reduced order model efficiency

- ❖ The reduced-order model simulation runtime achieves at least a 100x speedup compared to the full optical module simulation through INTERCONNECT with optical sample rate as 10 THz.

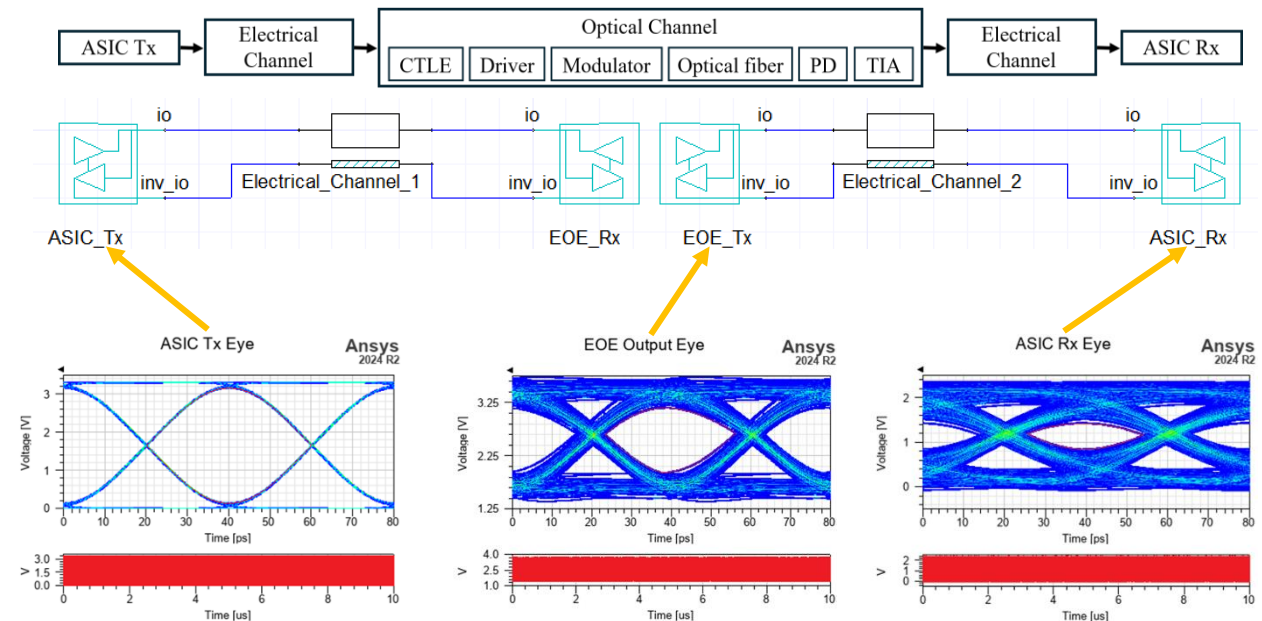
Simulation Run Time Benchmark

Simulation Time Window		30 ns	300 ns	3000 ns
Number of Random Bits		750	7,500	75,000
Simulation Run Time	INTERCONNECT	50 s	354 s	4640 s
	Reduced-Order Model	0.448 s	3.356 s	34.513 s



# IBIS-AMI simulation

- ❖ We built an AMI repeater testbench for a high-speed SerDes link, where the EOE\_Rx and EOE\_Tx represent for the optical module. The output of EOE\_Rx is automatically passed to EOE\_Tx as input, connecting the upstream and downstream links.
- ❖ AMI analysis was performed for a simulation time window of 10  $\mu$ s at bit rate of 25 Gbit/s (for a total of  $2.5 \times 10^5$  bits), and it took only 203 seconds runtime.
- ❖ The performance of optical module is well captured by the AMI model built by this flow.



# Summary

- We have developed an ML assisted workflow to create IBIS-AMI models for optical modules, enabling signal integrity analysis of advanced SerDes link:
  - This workflow provides powerful tools for users to extract an optical module into an AMI model with both high accuracy and high simulation efficiency.
  - The physical design IP of the optical module is protected in the AMI model.
  - The AMI model created in this workflow satisfies the standard IBIS-AMI specification.
  - The AMI model extracted in this workflow is portable and redistributable.
  - This workflow is highly automated, easy to use, and can be customized according to the design and modelling requirements.





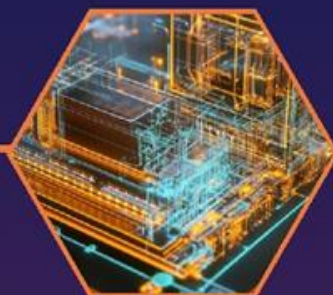
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